

TOSHIBA MOS MEMORY PRODUCTS

996 WORD x 8 BIT UV ERASABLE AND ELECTRICALLY
ROGRAMMABLE ROM
CHANNEL SILICON STACKED GATE MOS

TMM2732D
TMM2732D-2

DESCRIPTION

The TMM2732D is a 4096 word x 8 bit ultraviolet light erasable and electrically programmable read only memory. For read operation, the TMM2732D's maximum access time is 350ns/250ns, and the TMM2732D operates from a single 5-volt power supply and has a low power standby mode which reduces the power dissipation without increasing access time. The standby mode is achieved by applying a TTL-high level signal to the \overline{CE} input. The maximum active current is 150mA and the maximum standby current is 25mA/35mA.

FEATURES

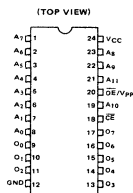
- Single 5-volt power supply
- Fast access time
 - TMM2732D . 350ns
 - TMM2732D-2 250ns
- Power dissipation
 - 150mA (Max.) (Active)
 - 25mA (Max.) (Standby TMM2732D)
 - 35mA (Max.) (Standby TMM2732D-2)
- Low power standby mode \overline{CE}

For program operation, the programming is achieved by applying a 50ms active TTL low program pulse to the \overline{CE} input, and it is possible to program sequentially, individually, or at random.

The TMM2732D is fabricated with the N-channel silicon double layer gate MOS technology and is packaged in a standard 24 pin dual in line cerdip package.

- Output buffer control \overline{OE}
- Fully Static operation
- Programs with one 50ms pulse
- Single location programming
- Total programming time about 200 seconds
- Three state outputs
- Inputs and Outputs
 - Directly TTL compatible
- Pin compatible with r2732 and ROM-TMM2332P

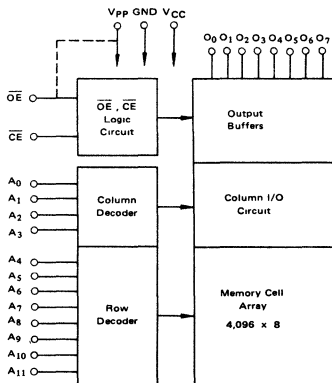
PIN CONNECTION



PIN NAMES

A ₀ ~ A ₁₁	Address Inputs
O ₀ ~ O ₇	Data Outputs (Inputs)
\overline{CE}	Chip Enable Input
\overline{OE}/V_{PP}	Output Enable Input/Program Power
V _{CC}	Power (+5V)
GND	Ground

BLOCK DIAGRAM



MODE SELECTION

MODE	PINS (NO.)	\overline{CE} (18)	\overline{OE}/V_{PP} (20)	V_{CC} (24)	Outputs (9-11, 13-17)
Read		V_{IL}	V_{IL}	+5V	D_{OUT}
Output Deselect		*	V_{IH}	+5V	High Impedance
Standby		V_{IH}	*	+5V	High Impedance
Program		V_{IL}	V_{PP}	+5V	D_{IN}
Program Verify		V_{IL}	V_{IL}	+5V	D_{OUT}
Program Inhibit		V_{IH}	V_{PP}	+5V	High Impedance

* V_{IH} or V_{IL} **MAXIMUM RATINGS**

SYMBOL	ITEM	RATING	UNIT
V_{CC}	V_{CC} Supply Voltage	-0.3 ~ 7.0	V
\overline{OE}/V_{PP}	Program Supply Voltage	-0.3 ~ 26.5	V
V_{IN}	Input Voltage	-0.3 ~ 7.0	V
V_{OUT}	Output Voltage	-0.3 ~ 7.0	V
P_D	Power Dissipation	1.6	W
T_{SOLDER}	Soldering Temperature Time	260 · 10	°C · sec
T_{STRG}	Storage Temperature	-65 ~ 125	°C
T_{OPR}	Operating Temperature	0 ~ 70	°C

READ OPERATION**D.C. RECOMMENDED OPERATING CONDITIONS**

SYMBOL	PARAMETER	MIN.	TYP.	MAX.	UNIT
V_{CC}	V_{CC} Supply Voltage	4.75	5.0	5.25	V
V_{IH}	Input High Voltage	2.0	—	$V_{CC} + 1.0$	V
V_{IL}	Input Low Voltage	-0.3	—	0.8	V

D.C. AND OPERATING CHARACTERISTICS(Ta = 0 ~ 70°C, V_{CC} = 5V ± 5%, unless otherwise noted)

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
I_{IL}	Input Load Current	$V_{IN} = 0 \sim 5.25V$	—	—	± 10	μA
I_{LO}	Output Leakage Current	$V_{OUT} = 0.4 \sim 5.25V$	—	—	± 10	μA
I_{CC1}	V_{CC} Current (Standby)	$\overline{CE} = V_{IH}$	—	—	25	mA
		TMM2732D-2	—	—	35	
I_{CC2}	V_{CC} Current (Active)	$\overline{CE} = V_{IL}$	—	—	150	mA
V_{OL}	Output Low Voltage	$I_{OL} = 2.1mA$	—	—	0.4	V
V_{OH}	Output High Voltage	$I_{OH} = -400\mu A$	2.4	—	—	V

A.C. CHARACTERISTICS

($T_a = 0 \sim 70^\circ\text{C}$, $V_{CC} = 5\text{V} \pm 5\%$, unless otherwise noted)

SYMBOL	PARAMETER	CONDITIONS	TMM2732D		TMM2732D-2		UNIT
			MIN.	MAX.	MIN.	MAX.	
t_{ACC}	Address Access Time	$\overline{CE} = \overline{OE} = V_{IL}$	—	350	—	250	ns
t_{CE}	\overline{CE} to Output Valid	$\overline{OE} = V_{IL}$	—	350	—	250	ns
t_{OE}	\overline{OE} to Output Valid	$\overline{CE} = V_{IL}$	—	120	—	100	ns
t_{DF1}	\overline{CE} to Output in High-Z	$\overline{OE} = V_{IL}$, $\overline{CE} = V_{IH}$	0	100	0	90	ns
t_{DF2}	\overline{OE} to Output in High-Z	$\overline{CE} = V_{IL}$, $\overline{OE} = V_{IH}$	0	100	0	90	ns
t_{OH}	Output Data Hold Time	$\overline{CE} = \overline{OE} = V_{IL}$	0	—	0	—	ns

A.C. TEST CONDITIONS

Output Load : 1 TTL Gate and C_L (100pF)
 Input Pulse Rise and Fall Times : ≤ 20 ns
 Input Pulse Levels : 0.8 ~ 2.2V
 Timing Measurement Reference Level : Inputs 1V and 2V
 Outputs 0.8V and 2V

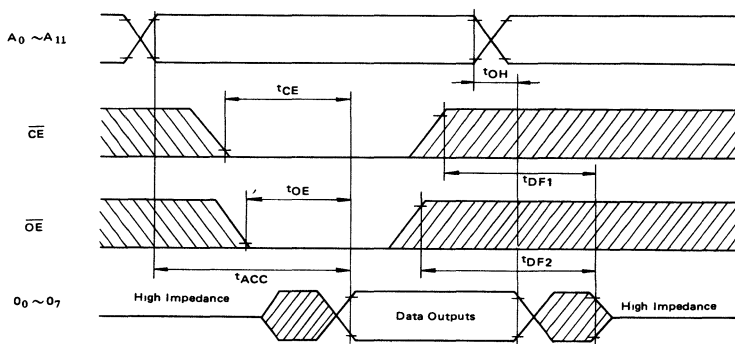
CAPACITANCE

(* $T_a = 25^\circ\text{C}$, $f = 1\text{MHz}$)

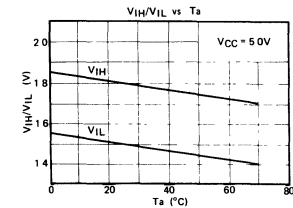
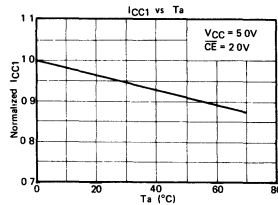
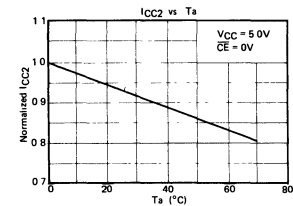
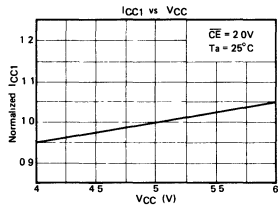
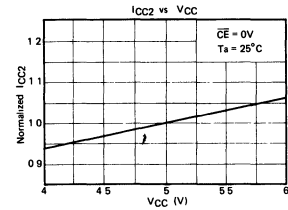
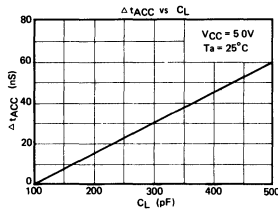
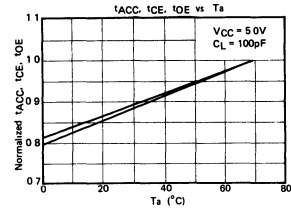
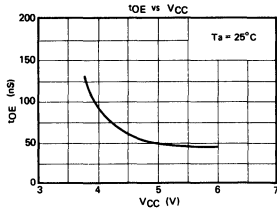
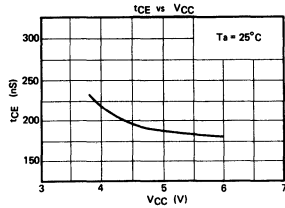
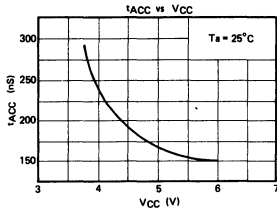
SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
C_{IN1}	Input Capacitance Except \overline{OE}/V_{PP}	$V_{IN} = 0\text{V}$	—	—	6	pF
C_{IN2}	Input Capacitance (\overline{OE}/V_{PP})	$V_{IN} = 0\text{V}$	—	—	20	pF
C_{OUT}	Output Capacitance	$V_{OUT} = 0\text{V}$	—	—	12	pF

* This parameter is periodically sampled and is not 100% tested

TIMING WAVEFORMS



TYPICAL CHARACTERISTIC DATA



PROGRAM OPERATION

D.C. RECOMMENDED OPERATING CONDITIONS

SYMBOL	PARAMETER	MIN	TYP.	MAX.	UNIT
V _{IH}	Input High Voltage	2.0	—	V _{CC} + 1.0	V
V _{IL}	Input Low Voltage	-0.3	—	0.8	V
V _{CC}	V _{CC} Supply Voltage	4.75	5.0	5.25	V
V _{PP}	Program Input Voltage	24	25	26	V

D.C. PROGRAMMING CHARACTERISTICS

(T_a = 25 ± 5°C, V_{CC} = 5V ± 5%, V_{PP} = 25V ± 1V)

SYMBOL	PARAMETER	CONDITIONS	MIN	TYP.	MAX.	UNIT
I _{LI}	Input Current	V _{IN} = 0 ~ 5.25V	—	—	± 10	μA
V _{OH}	Output High Voltage	I _{OH} = -400μA	2.4	—	—	V
V _{OL}	Output Low Voltage	I _{OL} = 2.1mA	—	—	0.4	V
I _{CC}	V _{CC} Supply Current	—	—	—	150	mA
I _{PP}	V _{PP} Supply Current	$\overline{CE} = V_{IL}, \overline{OE} = V_{PP}$	—	—	30	mA

A.C. PROGRAMMING CHARACTERISTICS

(T_a = 25 ± 5°C, V_{CC} = 5V ± 5%, V_{PP} = 25V ± 1V)

SYMBOL	PARAMETER	MIN.	TYP.	MAX.	UNIT
t _{AS}	Address Set Up Time	2	—	—	μs
t _{OES}	OE Set Up Time	2	—	—	μs
t _{DS}	Data Set Up Time	2	—	—	μs
(1)t _{AH}	Address Hold Time	0	—	—	μs
t _{OEH}	OE Hold Time	2	—	—	μs
t _{DH}	Data Hold Time	2	—	—	μs
t _{DF}	CE to Output in High-Z	—	—	100	ns
t _{CE}	\overline{CE} to Output Valid	—	—	350	ns
t _{PW}	Program Pulse Width	45	50	55	ms
t _{PRT}	V _{PP} Pulse Rise Time	50	—	—	ns
t _{VR}	V _{PP} Recovery Time	2	—	—	μs

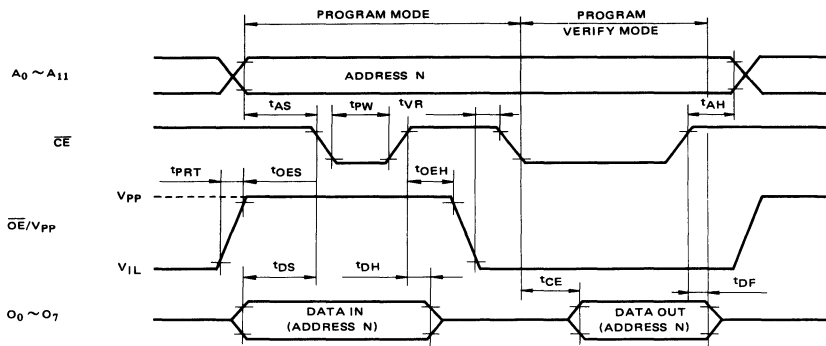
Note (1) t_{AH} (Program Operation 1) = 0μs min.
 t_{AH} (Program Operation 2) = 2μs min.
 Refer to Timing Waveforms

A.C. TEST CONDITIONS

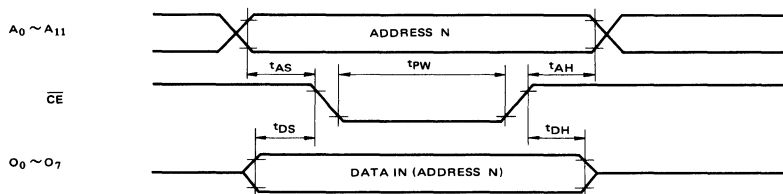
- Input Pulse Rise and Fall Times : ≤ 20ns
- Input Pulse Levels : 0.8V ~ 2.2V
- Timing Measurement Reference Level — Inputs : 1V & 2V
 Outputs : 0.8V & 2.0V

TIMING WAVEFORMS (PROGRAM OPERATION)

Program Operation 1.



Program Operation 2. (OE/Vpp = Vpp)



- Note**
1. V_{CC} must be applied simultaneously or before V_{pp} and cut off simultaneously or after V_{pp}
 2. Sometimes removing the device from socket and setting the device in socket under the condition $V_{pp} = 25V \pm 1V$ may cause permanent damage to the device.
 3. The V_{pp} supply voltage is permitted up to 26V for program operation, so the voltage over 26V should not be applied to the V_{pp} input. When the switching pulse voltage is applied to the V_{pp} input, the over-shoot voltage of its pulse should not be exceeded 26V

ERASURE CHARACTERISTICS

The TMM2732D's erasure is achieved by applying shortwave ultraviolet light which has a wavelength of 2537Å (Angstroms) to the chip through the transparent window. Then integrated does (ultraviolet light intensity [w/cm^2] x exposure time [sec.]) for erasure should be a minimum of 15 [$w. sec/cm^2$].

When the Toshiba sterilizing lamp GL-15 is used and the device is exposed at a distance of 1cm from the lamp surface, the erasure will be achieved within 60 minutes.

And using commercial lamps whose ultraviolet light intensity is a 12000 [$\mu w/cm^2$] will reduce the exposure time to about 20 minutes (In this case, the integrated does is 12000 [$\mu w/cm^2$] x (20 x 60) [sec] \cong 15 [$w. sec/cm^2$])

The TMM2732D's erasure begins to occur when exposed to light with wavelength shorter than 4000Å. The sunlight and the fluorescent lamps will include 3000 ~ 4000Å wavelength components. Therefore when used under such lighting for extended periods of time, the opaque seals - Toshiba EPROM Protect Seal AC901 - are available

OPERATION INFORMATION

The TMM2732D's six operation modes are listed in the following table. Mode selection can be achieved by applying TTL level signal to all inputs except for \overline{OE}/V_{PP} . In the read operation mode, a single 5-volt

power supply is required and the levels required for all inputs are TTL.

In the program operation mode the \overline{OE}/V_{PP} is pulsed from a TTL level to 25V.

MODE		PINS (NO.)	\overline{CE} (18)	\overline{OE}/V_{PP} (20)	V_{CC} (24)	$O_0 \sim O_7$ (9-11, 13-17)
READ	READ		V_{IL}	V_{IL}	+5V	DATA OUTPUT
OPERATION ($T_a = 0 \sim 70^\circ\text{C}$)	OUTPUT DESELECT		•	V_{IH}	+5V	HIGH IMPEDANCE
	STANDBY		V_{IH}	•	+5V	HIGH IMPEDANCE
PROGRAM	PROGRAM		V_{IL}	V_{PP}	+5V	DATA INPUT
OPERATION ($T_a = 25 \pm 5^\circ\text{C}$)	PROGRAM VERIFY		V_{IL}	V_{IL}	+5V	DATA OUTPUT
	PROGRAM INHIBIT		V_{IH}	V_{PP}	+5V	HIGH IMPEDANCE

- V_{IH} or V_{IL}

READ MODE

The TMM2732D has two control functions. Chip Enable (\overline{CE}) controls the operation power and should be used for device selection. Output Enable (\overline{OE}) controls the output buffers, independent of device selection.

Assuming that $\overline{CE} = \overline{OE} = V_{IL}$, the output data is valid at the outputs after address access time (350ns/

250ns max.) from stabilizing of the addresses.

The \overline{CE} to output valid (t_{CE}) is equal to the address access time.

Assuming that $\overline{CE} = V_{IL}$ and address are stable, the output data is valid at the outputs after t_{OE} (120ns/100ns max.) from the falling edge of \overline{OE} .

OUTPUT DESELECT MODE

Assuming that $\overline{OE} = V_{IH}$, the outputs will be in a high impedance state. So two or more TMM2732D's can be connected together on a common bus line.

When \overline{CE} is decoded for device selection, all deselected devices are in low power standby mode.

STANDBY MODE

The TMM2732D has a low power standby mode controlled by \overline{CE} signal. By applying a TTL high level signal to the \overline{CE} input, the TMM2732D is placed in the standby mode which reduce the operating cur-

rent from 150mA to 25mA/35mA, and then the outputs are in a high impedance state, independent of the \overline{OE} input.

PROGRAM MODE

Initially, when received by customers, all bits of the TMM2732D are in the '1' state which is erased state. Therefore the program operation is to introduce '0s' data into the desired bit locations by electrically programming. The TMM2732D is set up in the program operation mode when applied the program input voltage (+25V) to the \overline{OE}/V_{PP} input under $\overline{CE} = V_{IH}$.

Then programming is achieved by applying a 50ms active low TTL program pulse to the \overline{CE} input after

the addresses and data are stable. This program pulse should be a single pulse with 50ms pulse width per address word, and its maximum value is 55mS. The levels required for the address and data inputs are TTL. The TMM2732D can be programmed at any time individually, sequentially, or at random. The TMM2732D must not be programmed with a DC signal applied to the \overline{CE} input

PROGRAM VERIFY MODE

The verify mode is to check that the desired data is correctly programmed on the programmed bits. The verify is accomplished with \overline{OE}/V_{PP} and \overline{CE} at V_{IL} .

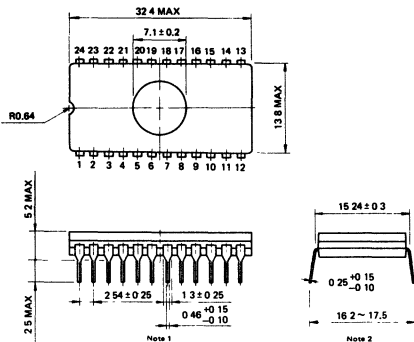
Data should be verified after t_{CE} (350ns max.) from the falling edge of \overline{CE} .

PROGRAM INHIBIT MODE

Under the condition that the program input voltage (+25V) is applied to the \overline{OE}/V_{PP} input, a TTL high level \overline{CE} input inhibits the TMM2732D from being programmed.

Programming of two or more TMM2732D's in parallel with different data is easily accomplished. That is, all inputs except for \overline{CE} are commonly connected, and the program pulse is applied to the \overline{CE} input of the desired device only and the TTL high level signal is applied to the other devices.

OUTLINE DRAWINGS



- Note 1 Each lead pitch is 2.54mm. All leads are located within 0.25mm of their true longitudinal position with respect to No. 1 and No. 24 leads.
- 2. This value is measured at the end of leads
- 3. All dimensions are in millimeters

©Nov. 1981 Toshiba Corporation